

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>		Complete if Known	
		Application Number	09/834,751
		Filing Date	April 13, 2001
		First Named Inventor	Velichko, Sergey
		Group Art Unit	2857
		Examiner Name	Miller, Craig
Sheet 1 of 1		Attorney Docket No: 303.750US1	

US PATENT DOCUMENTS

Examiner Initials*	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	Filing Date If Appropriate
✓	US-2002/0111775	08/15/2002	Dorough,			04/09/2002
	US-2003/0208340	11/06/2003	Dorough,			05/20/2003
	US-5,360,747	11/01/1994	Larson, S. O., et al.	438	10	06/10/1993
	US-5,806,181	09/15/1998	Khandros, I. Y., et al.	29	874	01/24/1997
	US-6,362,013	03/26/2002	Yoshimura, N.	438	14	04/26/2000
	US-6,370,487	04/09/2004	Dorough,			04/23/1999
	US-6,420,864	07/16/2002	Abraham, M. , et al.	324	158.1	04/13/2000
✓	US-6,466,314	10/15/2002	Lehman, Y.	356	237.1	09/17/1998
	US-6,567,770	05/20/2003	Dorough,			04/09/2002

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Foreign Document No	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	T ²

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
✓		DOROUGH, MICHAEL J., et al., "Dynamic Adaptable Semiconductor Testing", IEEE Proceedings of the 2002 International Symposium on Semiconductor Manufacturing, ISSM Catalog, (2002), 1-4	
✓		SEGEWICK, R. , Algorithms, Second Edition, Addison-Wesley Publishing Company, Inc.,(1988),pp. 516-519	

EXAMINER

DATE CONSIDERED

10/26/04

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <small>(See as many sheets as necessary)</small>		Complete if Known				
JAN 30 2004 <small>U.S. PATENT & TRADEMARK OFFICE</small> <small>Sheet 1 of 1</small>		Application Number	09/834751			
		Filing Date	April 13, 2001			
		First Named Inventor	Velichko, Sergey			
		Group Art Unit	2812			
		Examiner Name	Miller, Craig			
Attorney Docket No: 303.750US1						

US PATENT DOCUMENTS						
Examiner Initials*	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	Filing Date If Appropriate
	US20030028343	02/06/2003	Velichko, Sergey A., et al.	702	122	04/25/2002
	US20030212523	11/13/2003	Dorough, Michael J., et al.	702	119	04/25/2002
	US-5,241,266	08/31/1993	Ahmad, A. , et al.	714	733	04/10/1992
	US-5,457,400	10/10/1995	Ahmad, Aftab , et al.	324	763	07/23/1993
	US-5,483,175	01/09/1996	Ahmad, A. , et al.	438	18	03/09/1994
	US-5,726,920	03/10/1998	Chen, Susan H., et al.	702	108	09/29/1995
	US-5,787,190	07/28/1998	Peng, Y. , et al.	382	145	06/27/1997
	US-5,869,974	02/09/1999	Akram, Salman , et al.	324	754	04/01/1996
	US-5,962,862	10/05/1999	Evers, Sven , et al.	250	559.4	08/12/1997
	US-6,113,646	09/05/2000	Holden, B.	716	4	12/04/1997
	US-6,304,095	10/16/2001	Miyamoto, T.	324	765	11/30/1998
	US-6,314,034	11/06/2001	Sugamori, S.	365	201	04/14/2000
	US-6,383,825	05/07/2002	Farnworth, Warren M., et al.	438	14	07/10/2001
	US-6,445,199	09/03/2002	Satya, A. V., et al.	324	753	08/25/2000
	US-6,462,575	10/08/2002	Cram, Daniel P.	324	765	08/28/2000
	US-6,486,492	11/26/2002	Su, B.	257	48	11/20/2000
	US-6,505,138	01/07/2003	Leonard, L. S.	702	119	10/28/1999
	US-6,507,800	01/14/2003	Sheu, S.	702	117	03/13/2000
	US-6,536,006	03/18/2003	Sugamori, S.	714	724	11/12/1999
	US-6,618,682	09/09/2003	Bulaga, R. J., et al.	604	27	04/20/2001
	US-6,624,653	09/23/2003	Cram, Daniel P.	324	765	01/07/2002
	US-6,629,282	09/30/2003	Sugamori, S. , et al.	714	734	11/05/1999
	US-6,639,417	10/28/2003	Takao, T.	324	765	06/26/2001

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	
		BLUNN, R G., "Concurrent fault tolerant control of semiconductor measurement and testing", <u>2001 IEEE International Semiconductor Manufacturing Symposium</u> , (October 8-10, 2001), 455-458	

EXAMINER

DATE CONSIDERED

10/28/04